

- Controls 32 Electrodes
- 80-V (Ramped VCC2) Totem-Pole Outputs
- Low CMOS Stand-By Power Consumption
- Energy Recovery System Compatible
- 15-mA Source and Sink Compatibility
- High-Speed Serially-Shifted Data Input

description

The SN65559, SN65560, SN75559, and SN75560 are monolithic BiMOS[†] integrated circuits designed to provide the serial-to-parallel conversion and level translation of data in a matrix-addressable electroluminescent display. The device inputs are diode-clamped CMOS inputs. The SN65560 and SN75560 output sequences are reversed from the SN65559 and SN75559 for ease in printed circuit board layout.

These column drivers consist of a 32-bit static shift register, 32 latches, and 32 high-voltage outputs. Serial data is entered into the shift register on the low-to-high transition of the clock signal. A logic high signal on the Latch Enable input transfers the data from the shift register to the latches while the VCC2 bus is low. Once stable in the latch circuits, the VCC2 rail is ramped up to allow the data to appear at the high-voltage outputs. By limiting VCC2 to a maximum of 60 volts, these devices may be safely operated in a non-ramped VCC2 mode. Drivers may be cascaded via the serial data output of the static shift register. This output is not affected by the Latch Enable input.

The SN65559 and SN65560 are characterized for operation from -40°C to 85°C. The SN75559 and SN75560 are characterized for operation from 0°C to 70°C.

SN65559, SN75559
IN DUAL-IN-LINE PACKAGE

(TOP VIEW)

Q17	1	40	Q18
Q16	2	39	Q19
Q15	3	38	Q20
Q14	4	37	Q21
Q13	5	36	Q22
Q12	6	35	Q23
Q11	7	34	Q24
Q10	8	33	Q25
Q9	9	32	Q26
Q8	10	31	Q27
Q7	11	30	Q28
Q6	12	29	Q29
Q5	13	28	Q30
Q4	14	27	Q31
Q3	15	26	Q32
Q2	16	25	NC
Q1	17	24	DATA IN
SERIAL OUT	18	23	LATCH ENABLE
CLOCK	19	22	VCC1
GND	20	21	VCC2

3

Display Drivers

ADVANCE INFORMATION

SN65559, SN75559 . . . FN PACKAGE

(TOP VIEW)

Q12	1	4	3	2	1	44	43	42	41	40	Q21	Q22
6	6	4	3	2	1	44	43	42	41	40		
Q11	7										29	Q23
Q10	8										38	Q24
Q9	9										37	Q25
Q8	10										36	Q26
Q7	11										35	Q27
Q6	12										34	Q28
Q5	13										33	Q29
Q4	14										32	Q30
Q3	15										31	Q31
Q2	16										30	Q32
Q1	17										29	NC
SERIAL OUT	18	19	20	21	22	23	24	25	26	27	28	
	NC											
CLOCK												
GND												
VCC2												
VCC1												
LATCH ENABLE												
DATA IN												

NC—No internal connection

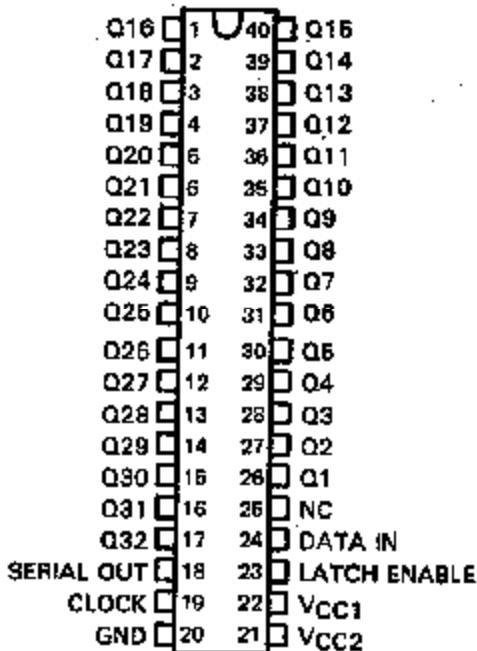
[†]BIDFET—Bipolar, double-diffused, N-channel and P-channel MOS transistors on the same chip—Patented Process

**SN65559, SN65560, SN75559, SN75560
ELECTROLUMINESCENT DISPLAY COLUMN DRIVERS**

**ADVANCE
INFORMATION**

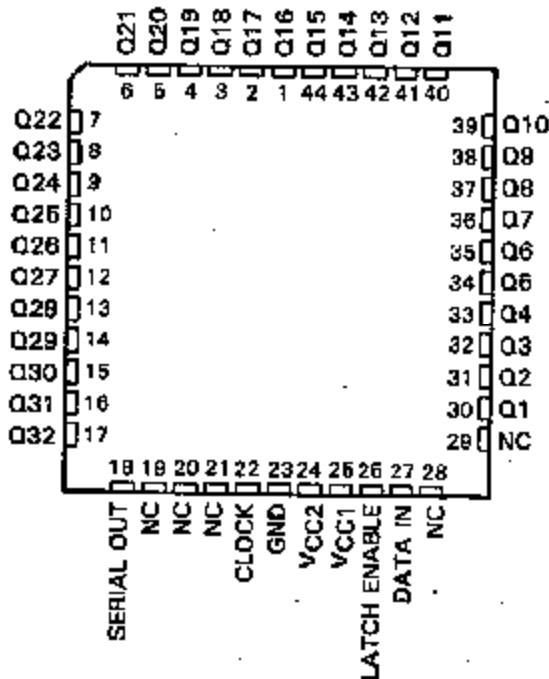
T-52-13-05

**SN65560, SN75560
IN DUAL-IN-LINE PACKAGE
(TOP VIEW)**



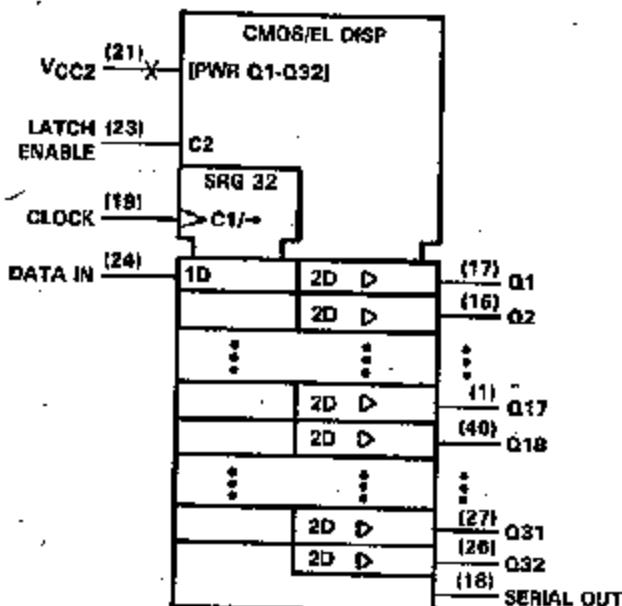
NC—No internal connection

**SN65560, SN75560 ... FN PACKAGE
(TOP VIEW)**

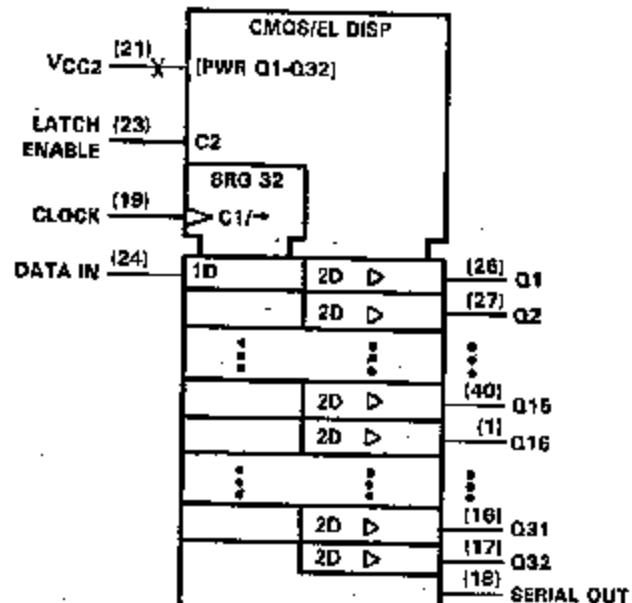


logic symbols†

SN65559, SN75559



SN65560, SN75560



† These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.
Pin numbers shown are for N packages.

T-52-13-05

FUNCTION TABLE

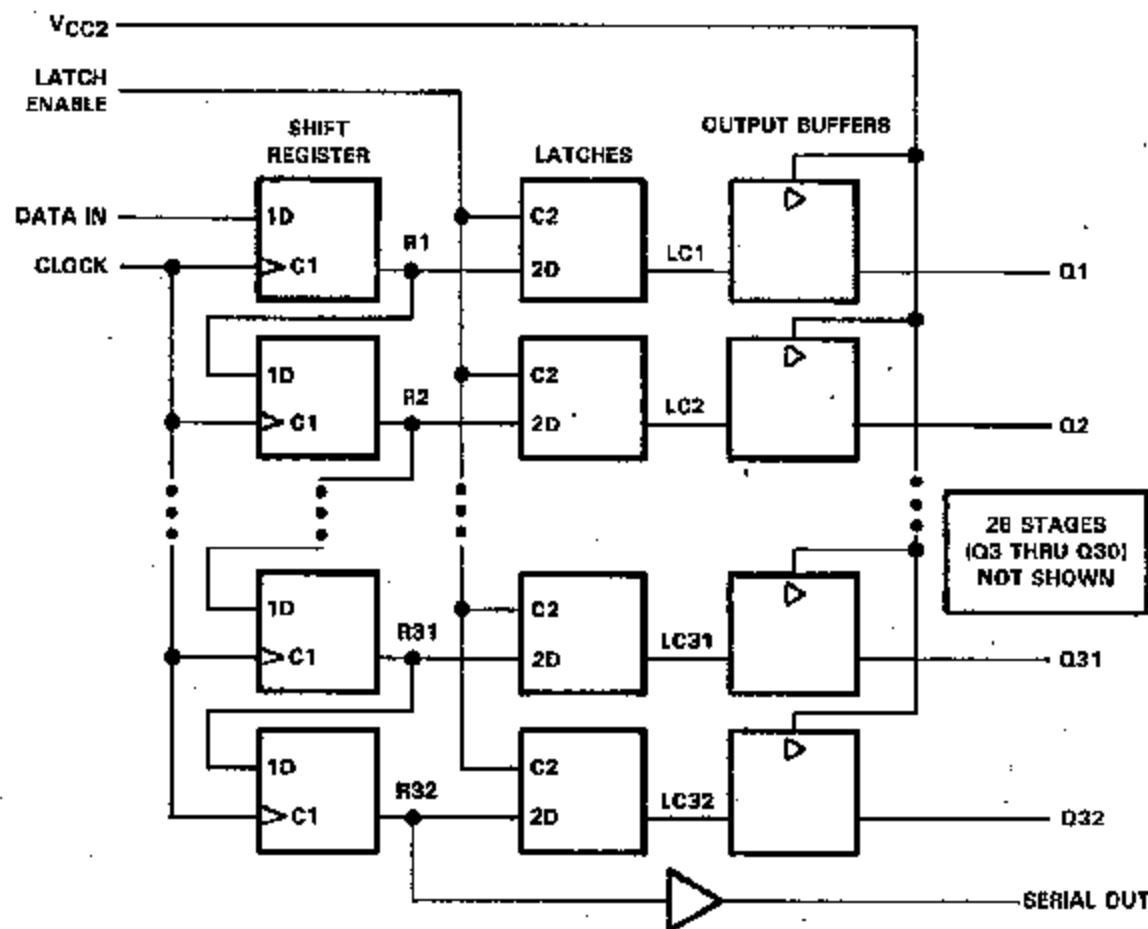
FUNCTION	CONTROL INPUTS		SHIFT REGISTERS R1 THRU R32	LATCHES LC1 THRU LC32	OUTPUTS	
	CLOCK	LATCH ENABLE†			SERIAL	Q1 THRU Q32
LOAD	T Net	X X	Load and Shift No change	Determined by Latch Enable	R32‡ R32	LC1 thru LC32 respectively
LATCH	X X	L H	As determined above	Stored data New data	R32 R32	LC1 thru LC32 respectively

H = high level; L = low level; X = irrelevant; † = low-to-high-level transition

† New data enters the latches while Latch Enable is high. These data are stored while Latch Enable is low.

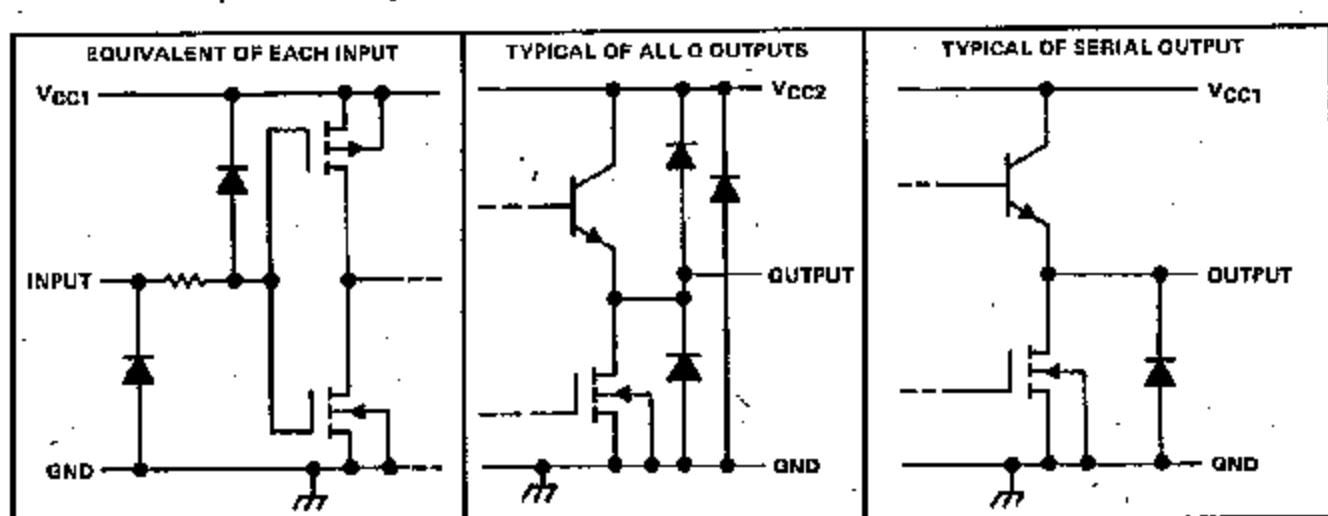
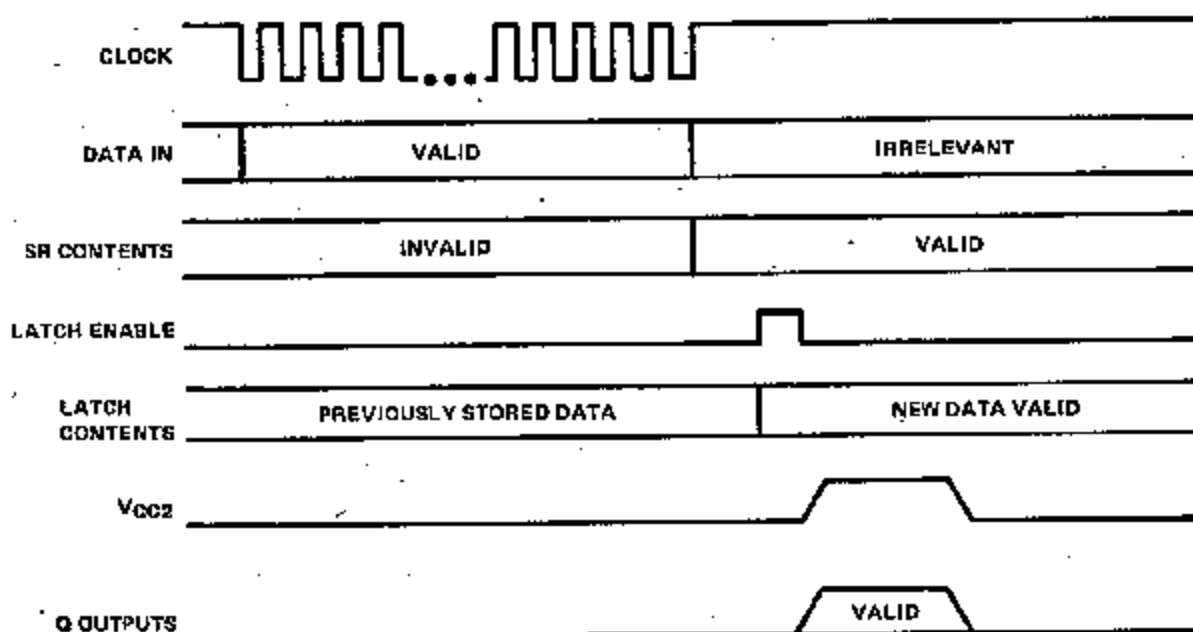
‡ R32 and the serial output take on the state of R31, R31 takes on the state of R30 . . . R2 takes on the state of R1 and R1 takes on the state of the data input.

logic diagram (positive logic)



T-52-13-05

typical operating sequence



T-52-13-05

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V _{CC1} (see Note 1)	18 V
Supply voltage, V _{CC2}	90 V
Input voltage, V _I	V _{CC1} +0.3 V
Continuous total dissipation at (or below) 25°C free-air temperature (see Note 2):	

N package	1250 mW
FN package	1700 mW

Operating free-air temperature range: SN65559, SN65560	-40°C to 85°C
SN75559, SN75560	0°C to 70°C

Storage temperature range	-65°C to 150°C
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Case temperature for 10 seconds: FN package	260°C
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Lead temperature 1.6 mm (1/16 inch) from case for 10 seconds: N package	260°C
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NOTES: 1. Voltage values are with respect to network ground terminal.

2. For operation above 25°C free-air temperature, derate the N package linearly at the rate of 10 mW/°C and the FN package at the rate of 13.6 mW/°C.

recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC1}	10.8	12	15	V
Supply voltage, V _{CC2}	0	80	90	V
High-level input voltage, V _{IH} (see Figure 1)	V _{CC1} = 10.8 V V _{CC1} = 15 V	8.1 11.25	11.1 15.3	V
Low-level input voltage, V _{IL} (see Figure 1)	V _{CC1} = 10.8 V V _{CC1} = 15 V	-0.3 -0.3	2.7 3.75	V
High-level Q output current, I _{OH}	-15			mA
Low-level Q output current, I _{OL}	15			mA
Q output clamp current, I _{OK}	-	20		mA
Clock frequency, f _{clock}	-	0	8	MHz
Pulse duration, clock high, t _{w(CLK)}	-	62		ns
Pulse duration, latch enable high, t _{w(LE)}	-	62		ns
Setup time, data before clock 1, t _{su}	-	20		ns
Hold time, data after clock 1, t _h	-	50		ns
Rate of rise of V _{CC2} , dv/dt (see Figure 4)	-	80		V/μs
Operating free-air temperature, T _A	SN65559, SN65560 SN75559, SN75560	-40 0	85 70	°C

NOTE 3: V_{CC2} must be ramped only when data within the latches is stable.electrical characteristics over recommended operating free-air temperature range, V_{CC1} = 12 V

PARAMETER		TEST CONDITIONS		MIN	MAX	UNIT
V _{OH} High-level output voltage	Q outputs	V _{CC2} = 80 V	I _{OH} = -15 mA	77		V
	Serial output	I _{OH} = 100 μA	-	10.5		
V _{OL} Low-level output voltage	Q outputs	I _{OL} = 15 mA	-	8		V
	Serial output	I _{OL} = 100 μA	-	1		
I _{IP} High-level input current	-	V _{IH} = V _{CC1}	-	1		μA
I _{IL} Low-level input current	-	V _{IL} = GND	-	-1		μA
I _{CC1} Supply current from V _{CC1}	V _I = V _{CC1}	-	-	500		μA
I _{CC2} Supply current from V _{CC2}	V _{CC2} = 80 V	Outputs low		-	3	
		Outputs high		-	0.5	mA

3

T-52-13-05

switching characteristics, V_{CC1} = 12 V, V_{CC2} = 0, T_A = 25°C

PARAMETER	FROM INPUT	TO OUTPUT	TEST CONDITIONS	MIN	MAX	UNIT
t _{PHL} Propagation delay time, high-to-low level	Clock	Serial Out	C _L = 20 pF, See Figure 3		140	ns
t _{PLH} Propagation delay time, low-to-high level	Clock	Serial Out	C _L = 20 pF, See Figure 3		140	ns
t _Q Delay time, V _{CC2} to Q output	V _{CC2}	Q	dV/dt = 80 V/μs, C _L = 100 pF, See Figure 4		100	ns

RECOMMENDED OPERATING CONDITIONS

INPUT VOLTAGE LOGIC-LEVEL LIMITS

vs
SUPPLY VOLTAGE V_{CC1}

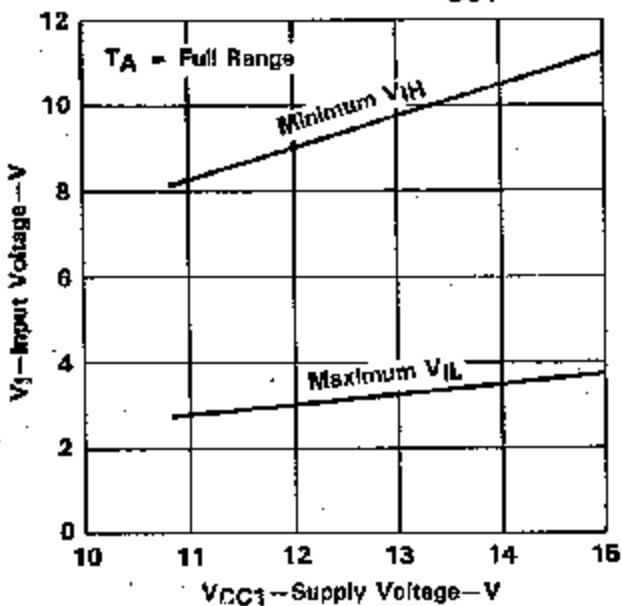


FIGURE 1

PARAMETER MEASUREMENT INFORMATION

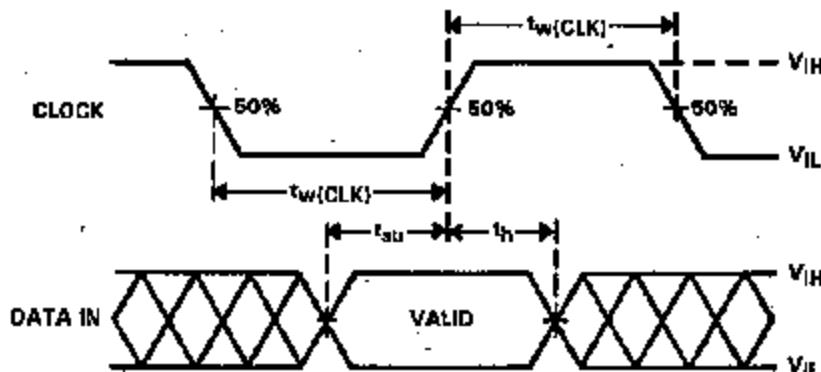


FIGURE 2. INPUT TIMING VOLTAGE WAVEFORMS

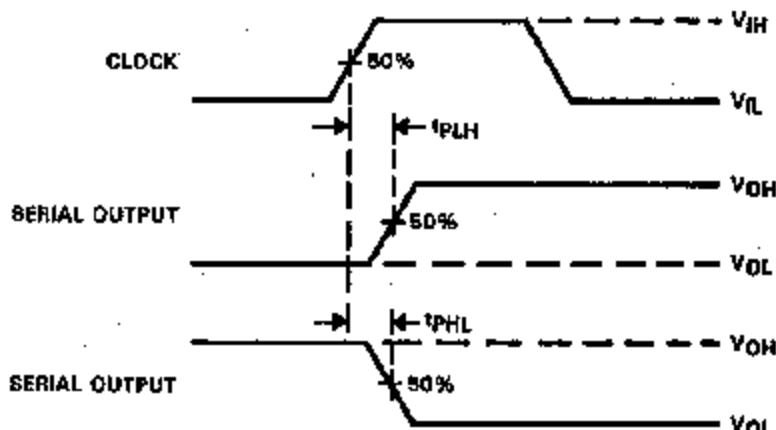


FIGURE 3. VOLTAGE WAVEFORMS FOR PROPAGATION DELAY CLOCK TO SERIAL OUTPUT

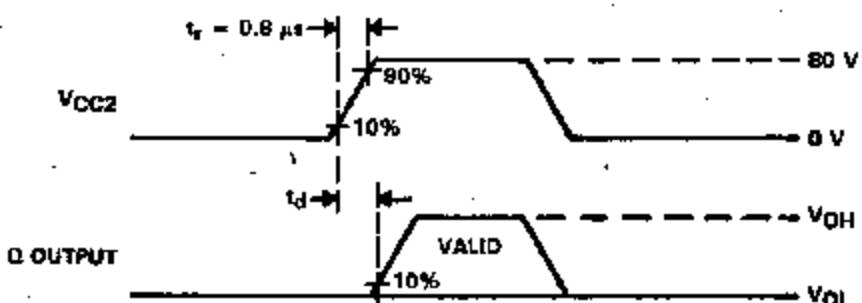


FIGURE 4. VOLTAGE WAVEFORMS FOR DELAY TIMES, LATCH ENABLE TO Q OUTPUTS